

Subscribe (Full Service) Register (Limited Service, Free) Login

Search: The ACM Digital Library The Guide

"delay element" "circuit configuration

Searching within The Guide for: "delay element" "circuit configuration" (start a new search) Found 7 of 1,568,378

## **REFINE YOUR SEARCH**

Refine by Keywords

"delay element" "circu

Discovered Terms

 Refine by People <u>Names</u> <u>Institutions</u> <u>Authors</u>

 Reline by Publications Publication Year Publication Names ACM Publications <u> All Publications</u> Content Formats Publishers

 Refine by Conterences Sponsors Events Proceeding Series

## **ADVANCED SEARCH**

Advanced Search

## **FEEDBACK**

Please provide us with <u>ieedback</u>

Found 7 of 1,568,378

Search Results Results 1 - 7 of 7 Related Journals

Related SIGs

Related Conferences

Sort by relevance

in expanded form

🤏 <u>Save results to a Binder</u>

Delay extraction-based passive macromodeling techniques for transmission line type interconnects characterized by tabulated multiport data

<u> Andrew Charest, Ram Achar, Michel Nakhla, Ihsan Erdin</u>

August 2009 Analog Integrated Circuits and Signal Processing, Volume 60 Issue 1-2

Publisher: Kluwer Academic Publishers

Additional Information: full citation, abstract, references

Bibliometrics: Downloads (6 Weeks): n/a, Downloads (12 Months): n/a, Downloads (Overall): n/a, Citation Count: 0

This paper introduces a novel algorithm for delay extraction-based passive macromodeling of multiconductor transmission line type interconnects characterized by multiport (Y, Z, S, or H) tabulated parameters. The algorithm determines a unique logarithm ...

Keywords: High-speed interconnects, Hybrid parameters, Macromodeling, Measurements, Tabulated data,

2 A delay measurement method using a shrinking clock signal

May 2010

Publisher: ACM ᡐ Request Fermissions Full text available: Pdf (414.00 KB)

Additional Information: full citation, abstract, references, index terms

Bibliometrics: Downloads (6 Weeks): 8, Downloads (12 Months): 14, Downloads (Overall): 14, Citation Count: 0

This paper describes a delay measurement method using a shrinking clock signal. The shrinking clock is generated from an AND operation on two clock signals having slightly different periods, which are provided by an external tester. Instead of measuring ...

Keywords: delay, edge placement accuracy, measurement, tester

3 Minimum delay optimization for domino logic circuits—a coupling-aware approach

<u>Ki-Wook Kim, Seong-Ook Jung, Taewhan Kim, Sung-Mo Kang</u>

April 2003 Transactions on Design Automation of Electronic Systems (TODAES), Volume 8 Issue 2

Publisher: ACM Paguest Permissions Full text available: Pat (130.81 KB)

Additional Information: full citation, abstract, references, index terms

Bibliometrics: Downloads (6 Weeks): 9, Downloads (12 Months): 39, Downloads (Overall): 410, Citation Count: 0

Minimum delay associated with the hold time requirement is of concern to circuit designers, since race-through hazards are inherent in any multiple clock organization or clock distribution tree irrespective of clock frequency. The monotonic property ...

Keywords: Logic synthesis, coupling, delay minimization, domino logic

4 Extracting RTL models from transistor netlists

K. J. Singh, P. A. Subrahmanyam December 1995 I CCAD '95: Proceedings of the 1995 IEEE/ ACM international conference on Computer-aided design Publisher: IEEE Computer Society

Full text available: Publisher Site , Pcf (119.32 KB) Additional Information: full citation, abstract, references, cited by, index terms

Bibliometrics: Downloads (6 Weeks): 4, Downloads (12 Months): 14, Downloads (Overall): 326, Citation Count: 3

This paper addresses the problem of deriving a register-transfer level (RTL) model from a transistor-level circuit. Using existing techniques, the transistor-level circuit is converted into a relation that describes the evolution of the signals in the ...

Keywords: Formal verification, Extraction, RTL model, Switch-level simulation

Evolutionary Synthesis of Arithmetic Circuit Structures <u> Takafum Aoki, Naofumi Homma, Tatsuo Higuchi</u>

December 2003 Artificial Intelligence Review, Volume 20 Issue 3-4

Publisher: Kluwer Academic Publishers

Full text available: Publisher Site

Additional Information: full citation, abstract, references, cited by, index terms

Bibliometrics: Downloads (6 Weeks): n/a, Downloads (12 Months): n/a, Downloads (Overall): n/a, Citation Count: 3

This paper presents an efficient graph-based evolutionary optimization technique called Evolutionary Graph Generation (EGG), and its application to arithmetic circuit synthesis. Key features of EGG are to employ a graphbased representation of individuals ...

Keywords: arithmetic circuits, circuit design, evolutionary computation, evolutionary design, genetic algorithms, genetic programming, multiple-valued logic

6 At-speed boundary-scan interconnect testing in a board with multiple system clocks

🎳 Jengchul Shin, Hyunjin Kim, Sungho Kang

January 1999 DATE '99: Proceedings of the conference on Design, automation and test in Europe

Publisher: ACM

Full text available: Pdf (200.12 KB)

Additional Information: full citation, references, cited by, index terms

Bibliometrics: Downloads (6 Weeks): 1, Downloads (12 Months): 11, Downloads (Overall): 74, Citation Count: 3

7 Simultaneous impulse stimulation and response sampling technique for built-in self test of linear analog

integrated circuits

<u> Wimol San-Um, Tachibana Masayoshi</u>

August 2009 SBCCI '09: Proceedings of the 22nd Annual Symposium on Integrated Circuits and System Design: Chip

on the Dunes

Publisher: ACM Acquest Permissions

Full text available: Pdf (2.12 MB)

Additional Information: full citation, abstract, references, index terms

Bibliometrics: Downloads (6 Weeks): 1, Downloads (12 Months): 24, Downloads (Overall): 24, Citation Count: 0

This paper proposes a new impulse stimulation and response sampling technique for the implementation of a Built-In Self Test of linear analog integrated circuits embedded in mixed-signal systems. The testing technique is the monitoring of physical fault ...

Keywords: built-in self test, impulse stimulation, linear analog integrated circuits, response sampling technique

The ACM Portal is published by the Association for Computing Machinery. Copyright © 2010 ACM, Inc. Terms of Usage Privacy Policy Code of Ethics Contact Us

Useful downloads: Adobe Acrobat QuickTime Windows Media Player